1. Record Nr. UNINA9910250058603321 Titolo 2017 IEEE International Test Conference (ITC) // Institute of Electrical and Electronics Engineers Staff Pubbl/distr/stampa Piscataway, New Jersey:,: Institute of Electrical and Electronics Engineers (IEEE), , 2017 1-5386-3413-9 **ISBN** Descrizione fisica 1 online resource (485 pages): illustrations Disciplina 621.38411 Soggetti Radio frequency Semiconductors - Testing Computer software - Testing Lingua di pubblicazione Inglese **Formato** Materiale a stampa Livello bibliografico Monografia Sommario/riassunto International Test Conference, the cornerstone of TestWeek events, is the premier conference dedicated to the electronic test of devices, boards and systems covering the complete cycle from design verification, test, diagnosis, failure analysis and back to process improvement At ITC, test and design professionals can confront the challenges the industry faces, and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment designers, and test engineers.